



HIGH SPEED, TRIPLE DIGITAL ISOLATORS

FEATURES

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- 25 and 150-Mbps Signaling Rate Options
 - Low Channel-to-Channel Output Skew; 1 ns max
 - Low Pulse-Width Distortion (PWD);
 2 ns max
 - Low Jitter Content; 1 ns Typ at 150 Mbps
- Typical 25-Year Life at Rated Working Voltage (See Application Note SLLA197 and Figure 14)
- 4000-V_{peak} Isolation, 560-V_{peak} V_{IORM}
 - UL 1577, IEC 60747-5-2 (VDE 0884, Rev 2), IE 61010-1 and CSA Approved
- 4 kV ESD Protection
- Operate With 3.3-V or 5-V Supplies

- High Electromagnetic Immunity (See Application Note SLLA181)
- –40°C to 125°C Operating Range

APPLICATIONS

- Industrial Fieldbus
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

DESCRIPTION

The ISO7230 and ISO7231 are triple-channel digital isolators each with multiple channel configurations and output enable functions. These devices have logic input and output buffers separated by TI's silicon dioxide (SiO_2) isolation barrier. Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents on a data bus or other circuits from entering the local ground and interfering with or damaging sensitive circuitry.

The ISO7230 triple-channel device has all three channels in the same direction while the ISO7231 has two channels in one direction and one channel in opposition. These devices have an active-high output enable that when driven to a low level, places the output in a high-impedance state.

The ISO7230C and ISO7231C have TTL input thresholds and a noise-filter at the input that prevents transient pulses of up to 2 ns in duration from being passed to the output of the device, while the ISO7230M and ISO7231M have CMOS $V_{CC}/2$ input thresholds and do not have the input noise-filter or the additional propagation delay.

In each device, a periodic update pulse is sent across the isolation barrier to ensure the proper dc level of the output. If this dc-refresh pulse is not received, the input is assumed to be unpowered or not being actively driven, and the failsafe circuit drives the output to a logic high state. (Contact TI for a logic low failsafe option).

These devices require two supply voltages of 3.3-V, 5-V, or any combination. All inputs are 5-V tolerant when supplied from a 3.3-V supply and all outputs are 4-mA CMOS. These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.

ISO7230 DW PACKAGE	DW PACKAGE		ISO7231 DW PACKAGE				
GND1	$\Box GND2 \\ \Box OUT_A \\ \Box OUT_B$	V _{CC1} GND1 INA INB OUT _C NC EN ₁	2 3 4 5 子	15 			
GND1 □ 8 ;; 9	III GND2	GND1 🞞	8	i 9			



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

FUNCTION DIAGRAM

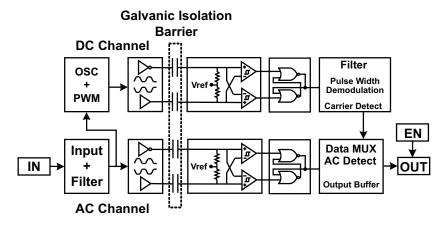


Table 1. Device Function Table ISO723x ⁽¹⁾

INPUT V _{CC}	OUTPUT V _{CC}	INPUT (IN)	OUTPUT ENABLE (EN)	OUTPUT (OUT)
		н	H or Open	Н
PU	PU	L	H or Open	L
PU	PU	Х	L	Z
			H or Open	Н
PD	PU	Х	H or Open	Н
PD	PU	Х	L	Z

(1) PU = Powered Up; PD = Powered Down ; X = Irrelevant; H = High Level; L = Low Level

AVAILABLE OPTIONS

PRODUCT	SIGNALING RATE	INPUT THRESHOLD	CHANNEL CONFIGURATION	MARKED AS	ORDERING NUMBER ⁽¹⁾
ISO7230CDW	25 Mbps	~1.5 V (TTL)		ISO7230C	ISO7230CDW (rail)
13072300000	25 10005	(CMOS compatible)	3/0	13072300	ISO7230CDWR (reel)
ISO7230MDW	150 Mhna		3/0	ISO7230M	ISO7230MDW (rail)
1507230101000	150 Mbps	Vcc/2 (CMOS)		1507230101	ISO7230MDWR (reel)
ISO7231CDW	OF Mhaa	~1.5 V (TTL)		IS07231C	ISO7231CDW (rail)
15072310000	25 Mbps	(CMOS compatible)	2/1	15072310	ISO7231CDWR (reel)
1007004 MDW/			2/1	100700414	ISO7231MDW (rail)
ISO7231MDW	150 Mbps	Vcc/2 (CMOS)		ISO7231M	ISO7231MDWR (reel)

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

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ABSOLUTE MAXIMUM RATINGS⁽¹⁾

					VALUE	UNIT	
V_{CC}	Supply voltage	ge ⁽²⁾ , V _{CC1} , V _{CC2}			–0.5 to 6	V	
VI	Voltage at IN	, OUT, EN			–0.5 to 6	V	
I _O	Output currer	nt			±15	mA	
		Human Body Model	JEDEC Standard 22, Test Method A114-C.01		±4		
ESD	Electrostatic discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1	kV	
		Machine Model	ANSI/ESDS5.2-1996	1	±200	V	
TJ	Maximum jur	iction temperature		170	°C		

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings (1) only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

All voltage values are with respect to network ground terminal and are peak voltage values. (2)

RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
V_{CC}	Supply voltage ⁽¹⁾ , V _{CC1} , V _{CC2}		3.15		5.5	V
I _{OH}	High-level output current				4	mA
I _{OL}	Low-level output current		-4			mA
		ISO723xC	40			
t _{ui}	Input pulse width	ISO723xM	6.67	5		ns
A /1		ISO723xC	0	30 ⁽²⁾	25	N 41
1/t _{ui}	Signaling rate	ISO723xM	0	200 ⁽²⁾	150	Mbps
VIH	High-level input voltage (IN)	100700.14	0.7 V _{CC}		V _{CC}	
V _{IL}	Low-level input voltage (IN)	- ISO723xM	0		0.3 V _{CC}	V
VIH	High-level input voltage (IN) (EN on all devices)	100700-0	2		V _{CC}	V
V _{IL}	Low-level input voltage (IN) (EN on all devices)	ISO723xC	0		0.8	v
TJ	Junction temperature				150	°C
Н	External magnetic field-strength immunity per IEC certification			1000	A/m	

For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.
 Typical sigalling rate under ideal conditions at 25°C.



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ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V $^{(1)}$ OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT			U			
	ISO7230C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no load,		1	3	mA
	1507230C/W	25 Mbps	EN ₂ at 3 V		7	9.5	mA
I _{CC1}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no load,		6.5	11	~ ^
	1507231C/M	25 Mbps	EN_1 at 3 V, EN_2 at 3 V		11	17	mA
	16070000/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no load,		15	22	~ ^
	ISO7230C/M	25 Mbps	EN ₂ at 3 V		17	24	mA
I _{CC2}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no load,		13	20	~ ^
	1507231C/M	25 Mbps	EN_1 at 3 V, EN_2 at 3 V		17.5	27	mA
ELECTR	RICAL CHARACTERISTIC	s					
I _{OFF}	Sleep mode output cur	rent	EN at 0 V, Single channel		0		μA
V	High-level output voltage		I _{OH} = -4 mA, See Figure 1	$V_{CC} - 0.8$			V
V _{OH}	High-level output volta	Je	$I_{OH} = -20 \ \mu A$, See Figure 1	$V_{CC} - 0.1$			v
V		•	I _{OL} = 4 mA, See Figure 1			0.4	V
V _{OL}	Low-level output voltag	е	$I_{OL} = 20 \ \mu A$, See Figure 1			0.1	v
V _{I(HYS)}	Input voltage hysteresi	6			150		mV
I _{IH}	High-level input current	t				10	۵
I _{IL}	Low-level input current		– IN from 0 V to V _{CC}	-10			μA
CI	Input capacitance to gr	ound	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transie	nt immunity	$V_{I} = V_{CC}$ or 0 V, See Figure 4	25	50		kV/μs

 $\begin{array}{ll} \mbox{(1)} & \mbox{For the 5-V operation, V}_{CC1} \mbox{ or V}_{CC2} \mbox{ is specified from 4.5 V to 5.5 V.} \\ & \mbox{For the 3-V operation, V}_{CC1} \mbox{ or V}_{CC2} \mbox{ is specified from 3.15 V to 3.6 V.} \end{array}$

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SWITCHING CHARACTERISTICS: V_{cc1} and V_{cc2} at 5-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	100700-0	See Figure 1	18		42	
PWD	Pulse-width distortion ⁽¹⁾ $ t_{PHL} - t_{PLH} $	– ISO723xC	See Figure 1			2.5	ns
t _{PLH} , t _{PHL}	Propagation delay	ISO723xM		10		23	20
PWD	Pulse-width distortion ⁽¹⁾ $ t_{PHL} - t_{PLH} $	1507238101			1	2	ns
	Part-to-part skew (2)	ISO723xC				8	
t _{sk(pp)}	Pan-to-part skew V	ISO723xM			0	3	ns
	Channel to channel output alray (3)	ISO723xC			0	2	20
t _{sk(o)}	Channel-to-channel output skew ⁽³⁾	ISO723xM			0	1	ns
t _r	Output signal rise time				2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-in	npedance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-	high-level output			15	20	
t _{PLZ}	Propagation delay, low-level-to-high-im	pedance output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		12		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, Same polarity inputon all channels, See Figure 5		1		ns

(1) Also referred to as pulse skew.

(2) t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

(3) $t_{sk(o)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

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INSTRUMENTS

EXAS

ELECTRICAL CHARACTERISTICS: V_{CC1} at 5-V, V_{CC2} at 3.3-V⁽¹⁾ OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETE	R	TEST CONDITIONS	6	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT							
	ISO7230C/M	Quiescent				1	3	mA
	15072300/10	25 Mbps	$v_1 = v_{CC}$ or 0 v, All channels, no los	$V_1 = V_{CC}$ or 0 V, All channels, no load, EN_2 at 3 V		7	9.5	mA
I _{CC1}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no los	ad, EN ₁ at 3 V,		6.5	11	mA
	13072310/10	25 Mbps	EN ₂ at 3 V			11	17	ША
	ISO7230C/M	Quiescent	$- V_{\rm r} = V_{\rm res} $ or $0 V_{\rm r}$ All channels no los	= V _{CC} or 0 V, All channels, no load, EN ₂ at 3 V		9	15	mA
1	13072300/10	25 Mbps		au, $\ln_2 a$ 5 v		10	17	
I _{CC2}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no loa	ad, EN ₁ at 3 V,		8	12	mA
	10072010/10	25 Mbps	EN ₂ at 3 V			10.5	16	ША
ELECTR	RICAL CHARACTE	RISTICS						
I _{OFF}	Sleep mode outp	out current	EN at 0 V, Single channel	EN at 0 V, Single channel		0		μΑ
				ISO7230	$V_{CC} - 0.4$			
V _{OH}	High-level output	t voltage		ISO7231 (5-V side)	$V_{CC} - 0.8$			V
			$I_{OH} = -20 \ \mu A$, See Figure 1		$V_{CC} - 0.1$			
V _{OL}	Low-level output	voltago	I _{OL} = 4 mA, See Figure 1				0.4	V
VOL		vollage	I _{OL} = 20 μA, See Figure 1				0.1	v
V _{I(HYS)}	Input voltage hys	steresis				150		mV
I _{IH}	High-level input	current	IN from 0 V to V _{CC}				10	μA
IIL	Low-level input of	current			-10]	μΑ
CI	Input capacitanc	e to ground	IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$			2		pF
CMTI	Common-mode to immunity	transient	$V_{I} = V_{CC}$ or 0 V, See Figure 4		25	50		kV/μs

(1) For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



SWITCHING CHARACTERISTICS: V_{CC1} at 5-V, V_{CC2} at 3.3-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay, low-to-high-level output	10070000	See Figure 1	20		50	~~
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	ISO723xC	See Figure 1			3	ns
t _{PLH} , t _{PHL}	Propagation delay, low-to-high-level output	ISO723xM		12		29	~~
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	150723XIVI			1	2	ns
+	Part-to-part skew ⁽²⁾	ISO723xC				10	20
t _{sk(pp)}	Part-to-part skew V	ISO723xM			0	5	ns
	Channel-to-channel output skew (3)	ISO723xC			0	2.5	~~~
t _{sk(o)}	Channel-to-channel output skew (**	ISO723xM			0	1	ns
t _r	Output signal rise time				2		
t _f	Output signal fall time		- See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-impeda	nce output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high-le	evel output			15	20	ns
t _{PLZ}	Propagation delay, low-level-to-high-impedar	ice output	- See Figure 2		15	20	
t _{PZL}	Propagation delay, high-impedance-to-low-le	vel output			15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		18		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

(1) Also known as pulse skew

(2) t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

(3) $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



EXAS

ELECTRICAL CHARACTERISTICS: V_{CC1} at 3.3-V, V_{CC2} at 5-V⁽¹⁾ OPERATION over recommended operating conditions (unless otherwise noted)

	PARAMETE	R	TEST CONDITIONS		MIN	TYP	MAX	UNIT
SUPPLY	CURRENT							
	ISO7230C/M	Quiescent	V/ V/ or 0.V/ All sharpeds no load			0.5	1	~ ^
	15072300/10	25 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no load,	EN ₂ at 3 v		3	5	mA
I _{CC1}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no load,	EN ₁ at 3 V,		4.5	7	mA
	13072310/10	25 Mbps	EN ₂ at 3 V			6.5	11	ША
	ISO7230C/M	Quiescent	$V_{\rm I} = V_{\rm CC}$ or 0 V, All channels, no load,	ENL of 2 \/		15	22	mA
	13072300/10	25 Mbps	$v_{\rm I} = v_{\rm CC}$ or v , All charmens, no load,	EN2 at 5 V		17	24	ША
I _{CC2}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no load,	EN ₁ at 3 V,		13	20	mA
	13072310/10	25 Mbps	EN ₂ at 3 V			17.5	27	ШA
ELECTR	RICAL CHARACTE	RISTICS						
I _{OFF}	Sleep mode outp	out current	rrent EN at 0 V, Single channel			0		μA
			I _{OH} = -4 mA, See Figure 1	ISO7230	$V_{CC} - 0.4$			
V _{OH}	High-level output	t voltage		ISO7231 (5-V side)	$V_{CC} - 0.8$			V
			$I_{OH} = -20 \ \mu A$, See Figure 1		V _{CC} - 0.1			
V		voltaga	I _{OL} = 4 mA, See Figure 1				0.4	V
V _{OL}	Low-level output	vollage	I _{OL} = 20 μA, See Figure 1				0.1	v
V _{I(HYS)}	Input voltage hys	steresis				150		mV
I _{IH}	High-level input	current	IN from 0 V to V _{CC}				10	
I _{IL}	Low-level input of	current			-10			μA
CI	Input capacitanc	e to ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$			2		pF
CMTI	Common-mode to immunity	transient	$V_{I} = V_{CC}$ or 0 V, See Figure 4		25	50		kV/μs

(1) For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.

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SWITCHING CHARACTERISTICS: V_{CC1} at 3.3-V and V_{CC2} at 5-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	10070040		22		51	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	ISO723xC				3	
t _{PLH} , t _{PHL}	Propagation delay	100700 14	- See Figure 1	12		30	ns
PWD	Pulse-width distortion ⁽¹⁾ $ t_{PHL} - t_{PLH} $	ISO723xM			1	2	
	Dent to ment allow (2)	ISO723xC				10	
t _{sk(pp)}	Part-to-part skew ⁽²⁾	ISO723xM			0	5	ns
	Channel-to-channel output skew (3)	ISO723xC			0	2.5	
t _{sk(o)}	Channel-to-channel output skew (**	ISO723xM	-		0	1	ns
t _r	Output signal rise time		See Figure 1		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-impedance	ce output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high-lev	el output			15	20	
t _{PLZ}	Propagation delay, low-level-to-high-impedance	e output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-leve	el output			15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		12		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

(1) Also known as pulse skew

(2) t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

(3) t_{sk(o)} is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

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ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3 $V^{(1)}$ OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN T	ΥP	MAX	UNIT
SUPPLY	CURRENT						
	10070000/04	Quiescent	$V_{I} = V_{CC}$ or 0 V, all channels, no load,		0.5	1	
	ISO7230C/M	25 Mbps	EN ₂ at 3 V		3	5	mA
I _{CC1}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, all channels, no load,		4.5	7	
	15072310/10	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		6.5	11	mA
	ISO7230C/M	Quiescent	$V_1 = V_{CC}$ or 0 V, all channels, no load,		9	15	
	15072300/101	25 Mbps	EN ₂ at 3 V		10	17	mA
I _{CC2}	ISO7231C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, all channels, no load,		8	12 16	
	15072310/10	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V	1	0.5		mA
ELECTR	ICAL CHARACTERISTICS						
I _{OFF}	Sleep mode output current		EN at 0 V, single channel		0		μA
V	High-level output voltage		I _{OH} = -4 mA, See Figure 1	$V_{CC} - 0.4$			V
V _{OH}	Tilgi-level output voltage		$I_{OH} = -20 \ \mu A$, See Figure 1	V _{CC} – 0.1			v
V _{OL}	Low-level output voltage		I _{OL} = 4 mA, See Figure 1			0.4	V
VOL	Low-level output voltage		$I_{OL} = 20 \ \mu A$, See Figure 1		0.		v
V _{I(HYS)}	Input voltage hysteresis			1	150		mV
I _{IH}	High-level input current		- IN from 0 V or V _{CC}			10	
I _{IL}	Low-level input current			-10			μA
CI	Input capacitance to ground		IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transient imr	nunity	$V_{I} = V_{CC}$ or 0 V, See Figure 4	25	50		kV/μs

(1) For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



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SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
t _{PLH} , t _{PHL}	Propagation delay	10070000	See Figure 1	25		56	20	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	- ISO723xC	See Figure 1			4	ns	
t _{pLH} , t _{pHL}	Propagation delay	ISO723xM		12		34	20	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} – t _{PLH}	1307232101			1	2	ns	
	Part to part along ⁽²⁾	ISO723xC				10		
t _{sk(pp)}	(pp) Part-to-part skew ⁽²⁾				0	5	5 ns	
	Channel-to-channel output skew (3)	ISO723xC			0	3	20	
t _{sk(o)}	Channel-to-channel output skew ()	ISO723xM			0	1	ns	
t _r	Output signal rise time		See Figure 1		2		20	
t _f	Output signal fall time	See Figure 1		2		ns		
t _{PHZ}	Propagation delay, high-level-to-high-impe	dance output			15	20		
t _{PZH}	Propagation delay, high-impedance-to-high-level output Propagation delay, low-level-to-high-impedance output				15	20		
t _{PLZ}			See Figure 2		15	20	ns 0	
t _{PZL}	Propagation delay, high-impedance-to-low			15	20			
t _{fs}	s Failsafe output delay time from input power loss		See Figure 3		18		μs	
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, same polarity input on all channels, See Figure 5		1		ns	

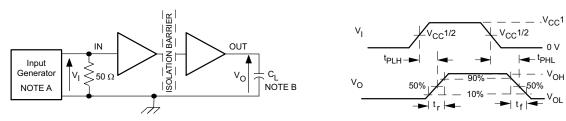
(1) Also referred to as pulse skew.

(2) t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

(3) $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

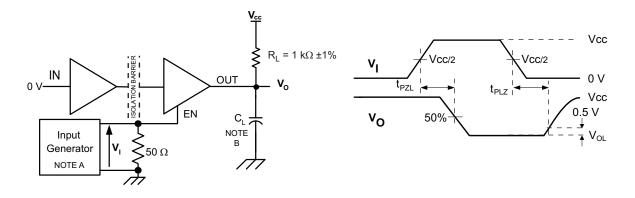


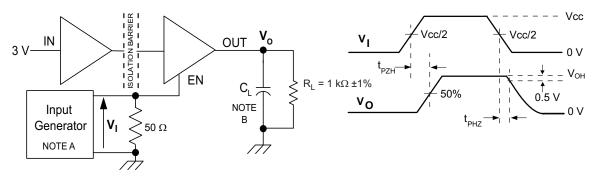
PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, Z₀ = 50 Ω .
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms



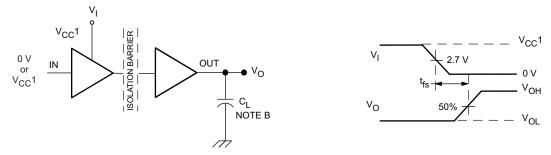


- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, Z₀ = 50 Ω .
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform

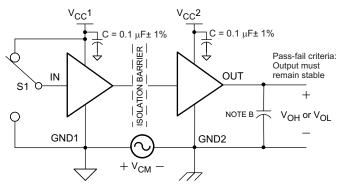


PARAMETER MEASUREMENT INFORMATION (continued)



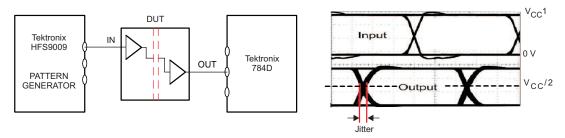
- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, Z_O = 50 Ω .
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, t_r \leq 3 ns, t_f \leq 3 ns, t_f \leq 3 ns, Z_O = 50 Ω .
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within ±20%.

Figure 4. Common-Mode Transient Immunity Test Circuit and Voltage Waveform



NOTE: PRBS bit pattern run length is 2¹⁶ – 1. Transition time is 800 ps. NRZ data input has no more than five consecutive 1s or 0s.

Figure 5. Peak-to-Peak Eye-Pattern Jitter Test Circuit and Voltage Waveform

TEXAS INSTRUMENTS

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DEVICE INFORMATION

PACKAGE CHARACTERISTICS

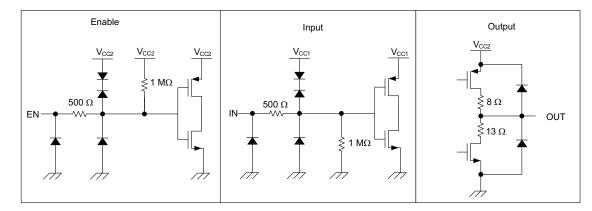
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	8.34			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	8.1			mm
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R _{IO}	Isolation resistance	Input to output, V_{IO} = 500 V, all pins on each side of the barrier tied together creating a two-terminal device, T_A < 100°C		>10 ¹²		Ω
		Input to output, $V_{IO} = 500 \text{ V}$, $100^{\circ}\text{C} \le \text{T}_{A} \le \text{T}_{A} \text{ max}$		>10 ¹¹		Ω
CIO	Barrier capacitance Input to output	V _I = 0.4 sin (4E6πt)		2		pF
CI	Input capacitance to ground	$V_{I} = 0.4 \sin (4E6\pi t)$		2		pF

REGULATORY INFORMATION

VDE	CSA	UL
Certified according to IEC 60747-5-2	Approved under CSA Component Acceptance Notice	Recognized under 1577 Component Recognition Program ⁽¹⁾
File Number: 40016131	File Number: 1698195	File Number: E181974

(1) Production tested \ge 3000 VRMS for 1 second in accordance with UL 1577.

DEVICE I/O SCHEMATICS

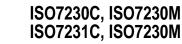


THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
0	Junction-to-air	Low-K Thermal Resistance ⁽¹⁾		168		°C/W
θ_{JA}	Junction-to-all	High-K Thermal Resistance		96.1		°C/W
θ_{JB}	Junction-to-Board Thermal Resistance			61		°C/W
θ_{JC}	Junction-to-Case Thermal Resistance			48		°C/W
PD	Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.5 \text{ V}, T_J = 150^{\circ}\text{C}, C_L = 15 \text{ pF},$ Input a 50% duty cycle square wave			220	mW

(1) Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

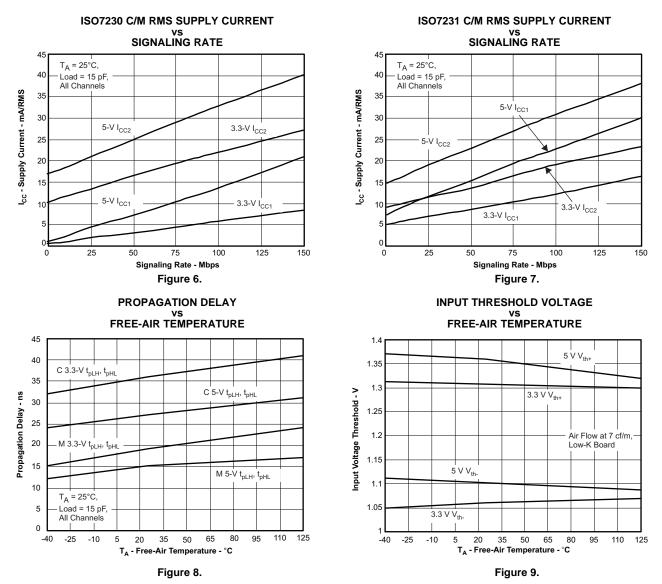




Texas

INSTRUMENTS

TYPICAL CHARACTERISTIC CURVES





TYPICAL CHARACTERISTIC CURVES (continued)

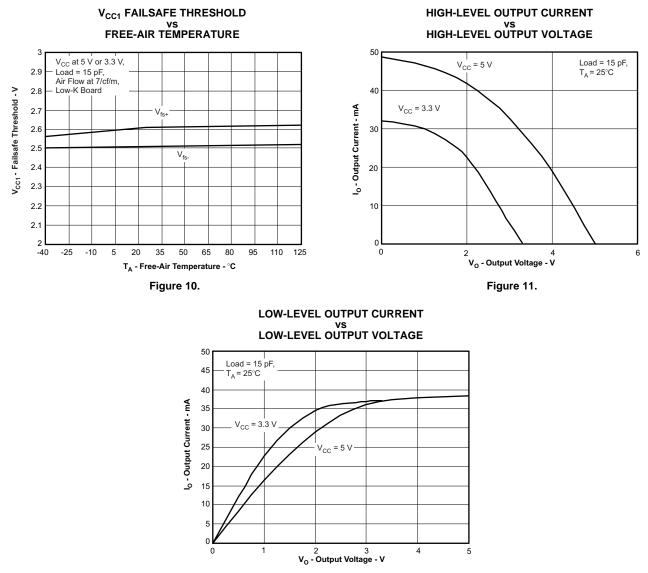


Figure 12.

Product Folder Link(s): ISO7230C, ISO7230M ISO7231C, ISO7230M



ISO7230C, ISO7230M ISO7231C, ISO7230M SLLS867F-SEPTEMBER 2007-REVISED JUNE 2008

www.ti.com

APPLICATION INFORMATION

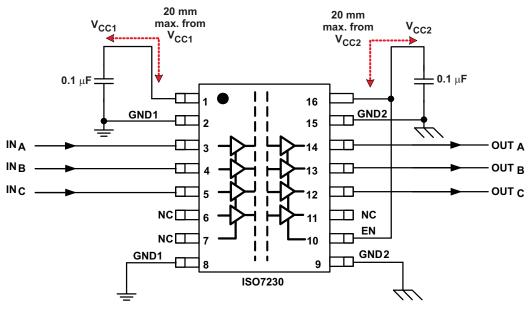


Figure 13. Typical ISO7230 Application Circuit

LIFE EXPECTANCY vs WORKING VOLTAGE

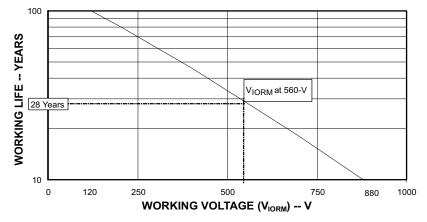


Figure 14. Time Dependant Dielectric Breakdown Testing Results

2-Jun-2008

PACKAGING INFORMATION

FRUME

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Packag Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
ISO7230CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7230MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
ISO7231MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)



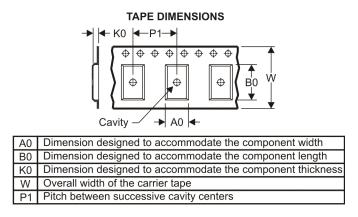
⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

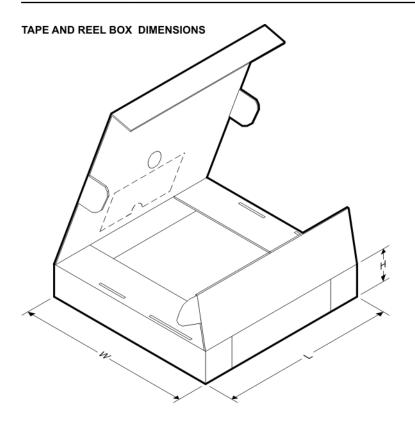


*All dimensions are nominal Device	Package	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7230CDWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1
ISO7230MDWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1
ISO7231CDWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1
ISO7231MDWR	SOIC	DW	16	2000	330.0	16.4	10.9	10.78	3.0	12.0	16.0	Q1



PACKAGE MATERIALS INFORMATION

2-Jun-2008



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7230CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7230MDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7231CDWR	SOIC	DW	16	2000	358.0	335.0	35.0
ISO7231MDWR	SOIC	DW	16	2000	358.0	335.0	35.0

DW (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AA.



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